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### Understanding Embedded - FPGAs (Field Programmable Gate Array)

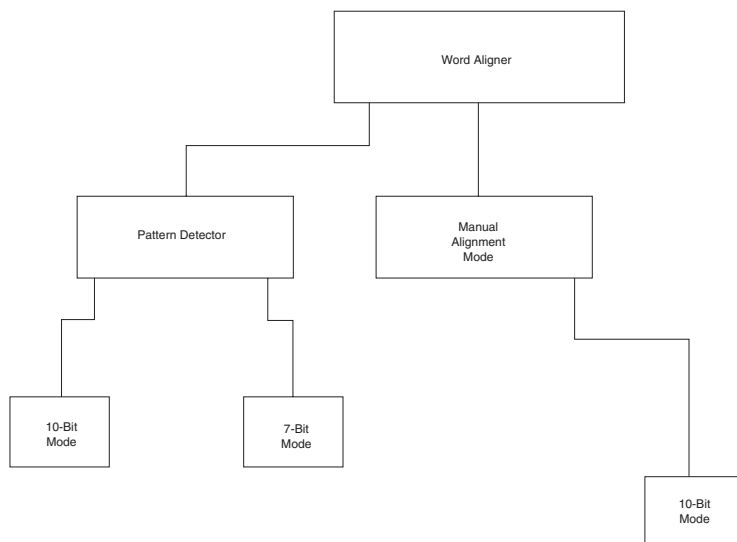
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	2566
Number of Logic Elements/Cells	25660
Total RAM Bits	1944576
Number of I/O	607
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1020-BBGA
Supplier Device Package	1020-FBGA (33x33)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/ep1sgx25ff1020c7n">https://www.e-xfl.com/product-detail/intel/ep1sgx25ff1020c7n</a>

**Figure 2–17. Word Aligner in 10-Bit Mode**

In the 10-bit mode, the word aligner automatically aligns the user's predefined 10-bit alignment pattern. The pattern detector can detect the full 10-bit pattern or only the lower seven bits of the pattern. The word aligner and pattern detector detect both the positive and the negative disparity of the pattern. A user-controlled enable port is available for the word aligner.

The 10-bit mode is available only for the Custom mode.

Figure 2–18 shows the word aligner in XAUI mode.

accurately tracked by the internal bias circuit. Moreover, the reference voltage and internal resistor bias current is generated and replicated to the analog circuitry in each channel.

### Hot-Socketing Capabilities

Each Stratix GX device is capable of hot-socketing. Because Stratix GX devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. Signals can be driven into Stratix GX devices before and during power-up without damaging the device. Once operating conditions are reached and the device is configured, Stratix GX devices operate according to your specifications. This feature provides the Stratix GX transceiver line card behavior, so you can insert it into the system without powering the system down, offering more flexibility.

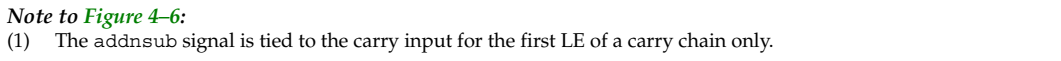
## Applications & Protocols Supported with Stratix GX Devices

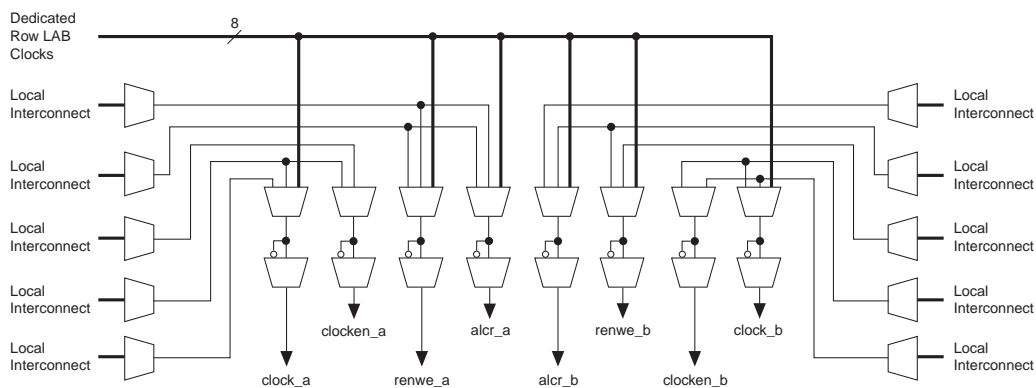
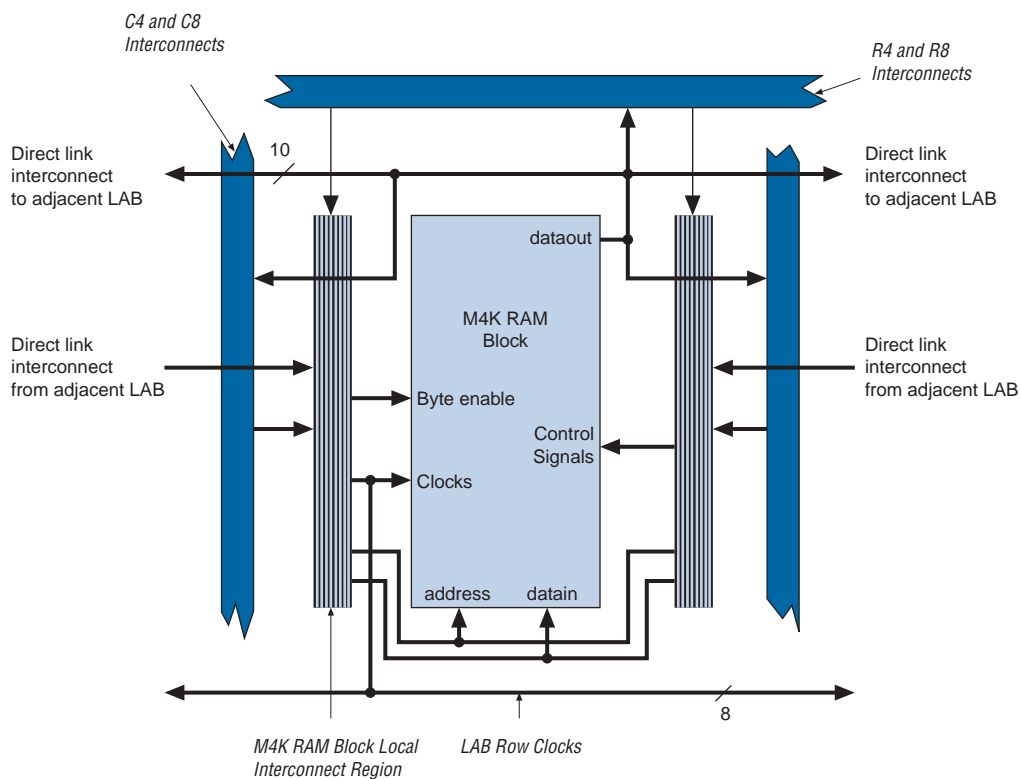
Each Stratix GX transceiver block is designed to operate at any serial bit rate from 500 Mbps to 3.1875 Gbps per channel. The wide, data rate range allows Stratix GX transceivers to support a wide variety of standard and future protocols such as 10-Gigabit Ethernet XAUI, InfiniBand, Fibre Channel, and Serial RapidIO. Stratix GX devices are ideal for many high-speed communication applications such as high-speed backplanes, chip-to-chip bridges, and high-speed serial communications standards support.

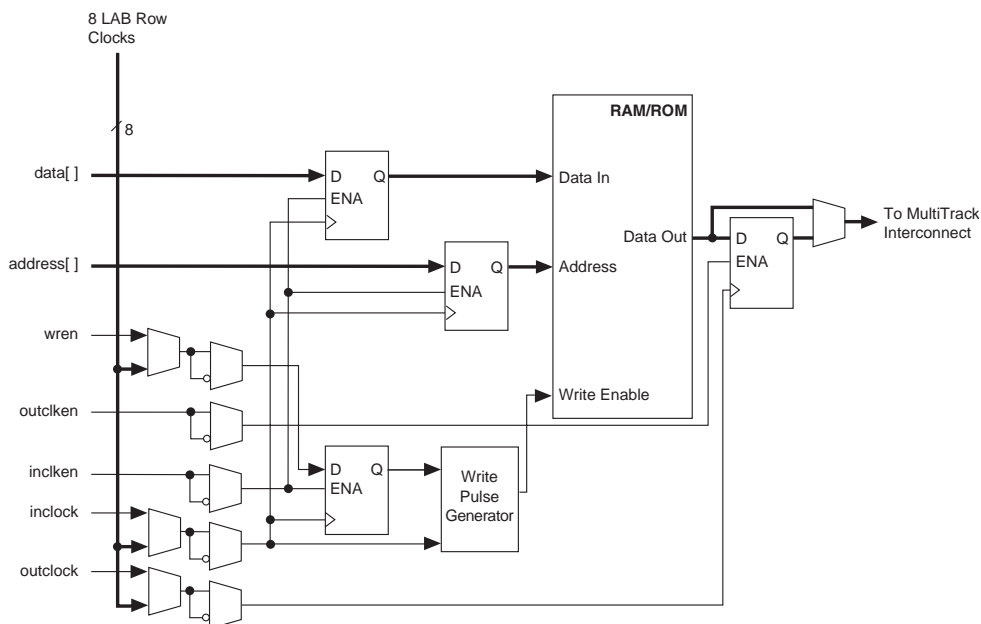
### Stratix GX Example Application Support

Stratix GX devices can be used for many applications, including:

- Backplanes for traffic management and quality of service (QoS)
- Switch fabric applications for complete set for backplane and switch fabric transceivers
- Chip-to-chip applications such as: 10 Gigabit Ethernet XAUI to XGMII bridge, 10 Gigabit Ethernet XGMII to POS-PHY4 bridge, POS-PHY4 to NPSI bridge, or NPSI to backplane bridge



**Figure 4–16. M4K RAM Block Control Signals****Figure 4–17. M4K RAM Block LAB Row Interface**

**Figure 4–27. Single-Port Mode**

## Digital Signal Processing Block

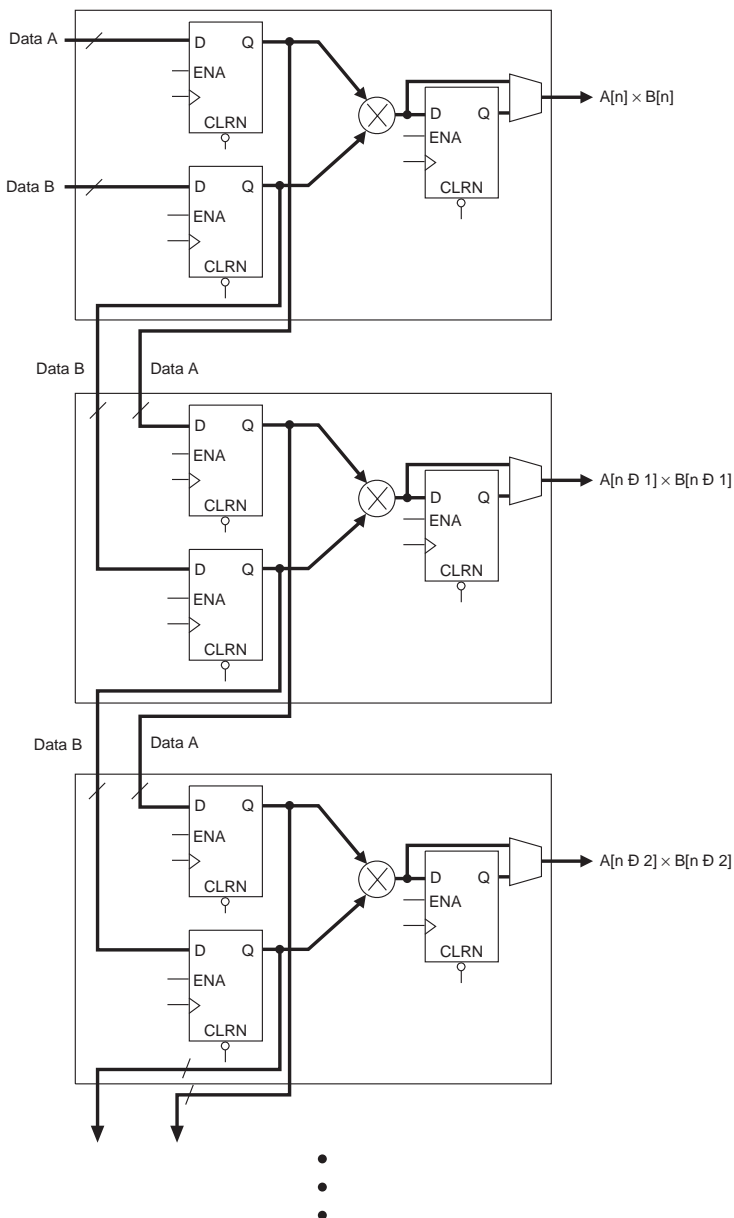
The most commonly used DSP functions are finite impulse response (FIR) filters, complex FIR filters, infinite impulse response (IIR) filters, fast Fourier transform (FFT) functions, direct cosine transform (DCT) functions, and correlators. All of these blocks have the same fundamental building block: the multiplier. Additionally, some applications need specialized operations such as multiply-add and multiply-accumulate operations. Stratix GX devices provide DSP blocks to meet the arithmetic requirements of these functions.

Each Stratix GX device has two columns of DSP blocks to efficiently implement DSP functions faster than LE-based implementations. Larger Stratix GX devices have more DSP blocks per column (see [Table 4–12](#)). Each DSP block can be configured to support up to:

- Eight  $9 \times 9$ -bit multipliers
- Four  $18 \times 18$ -bit multipliers
- One  $36 \times 36$ -bit multiplier

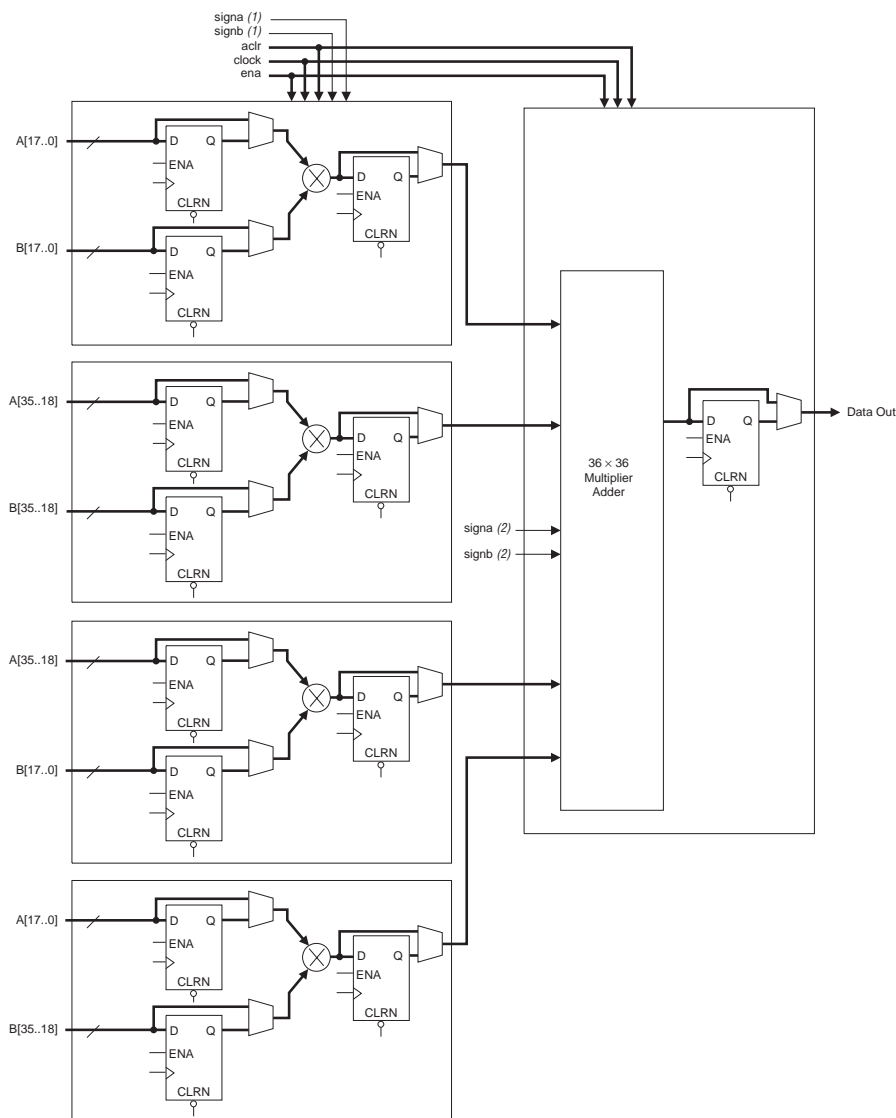
As indicated, the Stratix GX DSP block can support one  $36 \times 36$ -bit multiplier in a single DSP block. This is true for any matched sign multiplications (either unsigned by unsigned or signed by signed), but

**Figure 4–32. Multiplier Sub-Blocks Using Input Shift Register Connections** *Note (1)*



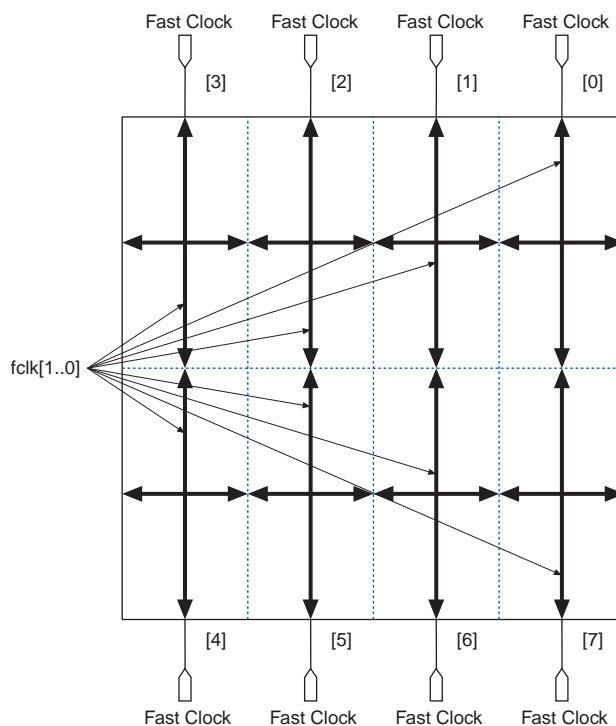
**Note to Figure 4–32:**

(1) Either Data A or Data B input can be set to a parallel input for constant coefficient multiplication.

**Figure 4–35.  $36 \times 36$  Multiply Mode****Notes to Figure 4–35:**

- (1) These signals are not registered or registered once to match the pipeline.
- (2) These signals are not registered, registered once, or registered twice for latency to match the pipeline.

**Figure 4–44. EP1SGX40 Device Fast Regional Clock Pin Connections to Fast Regional Clocks**



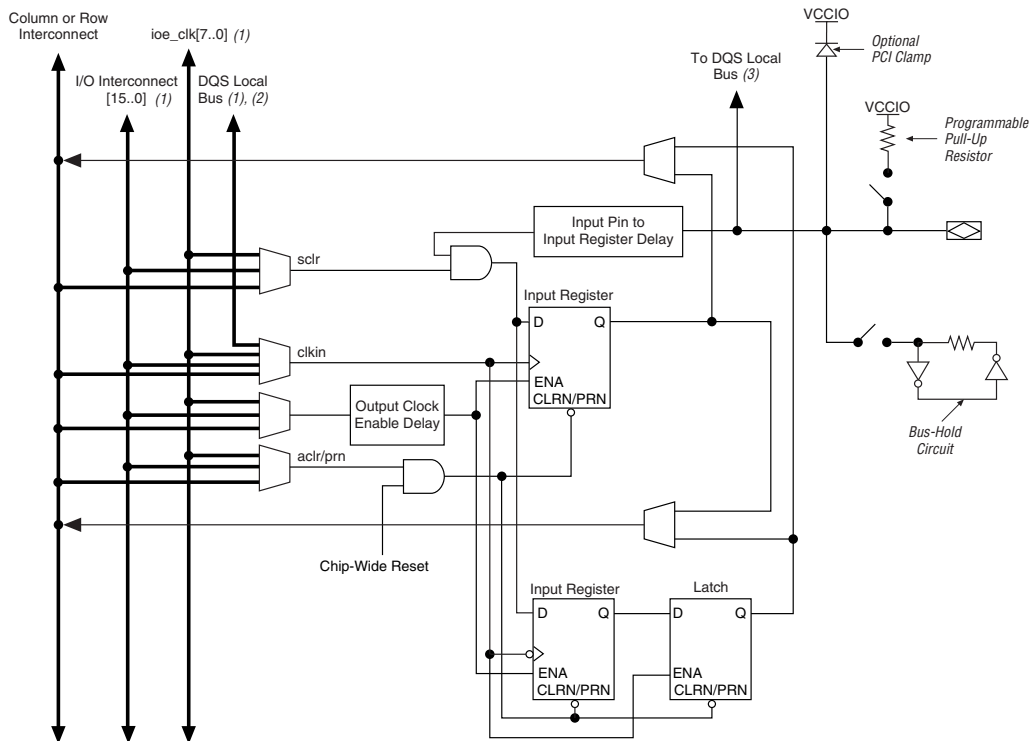
### Combined Resources

Within each region, there are 22 distinct dedicated clocking resources consisting of 16 global clock lines, 4 regional clock lines, and 2 fast regional clock lines. Multiplexers are used with these clocks to form 8-bit busses to drive LAB row clocks, column IOE clocks, or row IOE clocks. Another multiplexer at the LAB level selects two of the eight row clocks to feed the LE registers within the LAB. See [Figure 4–45](#).

When using the IOE for DDR inputs, the two input registers clock double rate input data on alternating edges. An input latch is also used within the IOE for DDR input acquisition. The latch holds the data that is present during the clock high times. This allows both bits of data to be synchronous with the same clock edge (either rising or falling).

Figure 4–64 shows an IOE configured for DDR input. Figure 4–65 shows the DDR input timing diagram.

**Figure 4–64. Stratix GX IOE in DDR Input I/O Configuration** *Note (1)*



**Notes to Figure 4–64:**

- (1) All input signals to the IOE can be inverted at the IOE.
- (2) This signal connection is only allowed on dedicated DQ function pins.
- (3) This signal is for dedicated DQS function pins only.

## Slew-Rate Control

The output buffer for each Stratix GX device I/O pin has a programmable output slew-rate control that can be configured for low-noise or high-speed performance. A faster slew rate provides high-speed transitions for high-performance systems. However, these fast transitions may introduce noise transients into the system. A slow slew rate reduces system noise, but adds a nominal delay to rising and falling edges. Each I/O pin has an individual slew-rate control, allowing you to specify the slew rate on a pin-by-pin basis. The slew-rate control affects both the rising and falling edges.

## Bus Hold

Each Stratix GX device I/O pin provides an optional bus-hold feature. The bus-hold circuitry can weakly hold the signal on an I/O pin at its last-driven state. Since the bus-hold feature holds the last-driven state of the pin until the next input signal is present, an external pull-up or pull-down resistor is not needed to hold a signal level when the bus is tri-stated.

Table 4–25 shows bus hold support for different pin types.

<b>Table 4–25. Bus Hold Support</b>	
<b>Pin Type</b>	<b>Bus Hold</b>
I/O pins	✓
CLK [15 . . 0]	
CLK [0, 1, 2, 3, 8, 9, 10, 11]	
FCLK	✓
FPLL [7 . . 10] CLK	

The bus-hold circuitry also pulls undriven pins away from the input threshold voltage where noise can cause unintended high-frequency switching. You can select this feature individually for each I/O pin. The bus-hold output drives no higher than  $V_{CCIO}$  to prevent overdriving signals. If the bus-hold feature is enabled, the programmable pull-up option cannot be used. Disable the bus-hold feature when using open-drain outputs with the GTL+ I/O standard or when the I/O pin has been configured for differential signals.

**Table 4–33. Stratix GX JTAG Instructions (Part 2 of 2)**

JTAG Instruction	Description
CLAMP (1)	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding I/O pins to a state defined by the data in the boundary-scan register.
ICR instructions	Used when configuring a Stratix GX device through the JTAG port with a MasterBlaster™ or ByteBlasterMV™ download cable, or when using a .jam file or .jbc file with an embedded processor.
PULSE_NCONFIG	Emulates pulsing the nCONFIG pin low to trigger reconfiguration even though the physical pin is unaffected.
CONFIG_IO	Allows the IOE standards to be configured through the JTAG chain. Stops configuration if executed during configuration. Can be executed before or after configuration.
SignalTap instructions	Monitors internal device operation with the SignalTap embedded logic analyzer.

**Note to Table 4–33:**

- (1) Bus hold and weak pull-up resistor features override the high-impedance state of HIGHZ, CLAMP, and EXTEST.

The Stratix GX device instruction register length is 10 bits, and the USERCODE register length is 32 bits. Tables 4–34 and 4–35 show the boundary-scan register length and IDCODE information for Stratix GX devices.

**Table 4–34. Stratix GX Boundary-Scan Register Length**

Device	Boundary-Scan Register Length
EP1SGX10	1,029
EP1SGX25	1,665
EP1SGX40	1,941

**Table 4–35. 32-Bit Stratix GX Device IDCODE (Part 1 of 2)**

Device	IDCODE (32 Bits) (1)			
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer Identity (11 Bits)	LSB (1 Bit) (2)
EP1SGX10	0000	0010 0000 0100 0001	000 0110 1110	1
EP1SGX25	0000	0010 0000 0100 0011	000 0110 1110	1

### Operating Conditions

Stratix® GX devices are offered in both commercial and industrial grades. However, industrial-grade devices may have limited speed-grade availability.

Tables 6–1 through 6–12 provide information on absolute maximum ratings, recommended operating conditions, DC operating conditions, and transceiver block absolute maximum ratings. Notes for Tables 6–1 through 6–6 immediately follow Table 6–6, notes for Table 6–7 immediately follow that table, and notes for Tables 6–8 through 6–12 immediately follow Table 6–12.

**Table 6–1. Stratix GX Device Absolute Maximum Ratings** Notes (1), (2)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
$V_{CCINT}$	Supply voltage	With respect to ground (3)	–0.5	2.4	V
$V_{CCIO}$			–0.5	4.6	V
$V_I$	DC input voltage		–0.5	4.6	V
$I_{OUT}$	DC output current, per pin		–25	25	mA
$T_{STG}$	Storage temperature	No bias	–65	150	° C
$T_{AMB}$	Ambient temperature	Under bias	–65	135	° C
$T_J$	Junction temperature	BGA packages under bias		135	° C

**Table 6–2. Stratix GX Device Recommended Operating Conditions (Part 1 of 2)** Note (7), (12), (13)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
$V_{CCINT}$	Supply voltage for internal logic and input buffers	(4)	1.425	1.575	V
$V_{CCIO}$	Supply voltage for output buffers, 3.3-V operation	(4), (5)	3.00 (3.135)	3.60 (3.465)	V
	Supply voltage for output buffers, 2.5-V operation	(4)	2.375	2.625	V
	Supply voltage for output buffers, 1.8-V operation	(4)	1.71	1.89	V
	Supply voltage for output buffers, 1.5-V operation	(4)	1.4	1.6	V
$V_I$	Input voltage	(3), (6)	–0.5	4.1	V

**Table 6–7. Stratix GX Transceiver Block AC Specification (Part 4 of 7)**

Symbol / Description	Conditions	-5 Commercial Speed Grade (1)			-6 Commercial & Industrial Speed Grade (1)			-7 Commercial & Industrial Speed Grade (1)			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Sinusoidal jitter	f = 22.1 kHz at 3.125 Gbps			8.5			8.5			N/A	
	f = 1.875 MHz at 3.125 Gbps			0.1			0.1			N/A	
	f = 20 MHz at 3.125 Gbps			0.1			0.1			N/A	
BER (12)				10 <sup>-12</sup>			10 <sup>-12</sup>			10 <sup>-12</sup>	
Receive latency (4)	Single width	7		32	7		32	7		32	(3)
	Double width	5		19	5		19	5		19	(3)
Channel to channel bit skew tolerance (5), (6)	XAUI mode / inter-quadrant only			40			40			N/A	UI (7)
Run-length	(8)			80			80			80	UI
Receive return loss (differential)	100 MHz to 2.5 Ghz			–10			–10			–10	dB
Receive return loss (common mode)	100 MHz to 2.5 Ghz			–6			–6			–6	dB
<b>Transmitter</b>											
Serial data rate	Commercial / industrial	500		3,187.5	500		3,187.5	500		2,500	Mbps
Parallel transceiver/core interface speed		20		398.4	20		375	20		312.5	MHz
<b>8B/10B Custom Transmitter Jitter using Encoded CRPAT</b> <i>Note (9)</i>											
Deterministic jitter	500 Mbps Pre-emphasis = 1			0.11			0.11			0.11	UI
Total jitter	V <sub>OD</sub> = 1,400 mV			0.18			0.18			0.18	UI

**Table 6–35. Stratix GX Device Performance (Part 2 of 3)** *Notes (1), (2)*

Applications		Resources Used			Performance			
		LEs	TriMatrix Memory Blocks	DSP Blocks	-5 Speed Grade	-6 Speed Grade	-7 Speed Grade	Units
TriMatrix memory M512 block	Simple dual-port RAM 32 × 18 bit	0	1	0	317.76	277.62	241.48	MHz
	FIFO 32 × 18 bit	30	1	0	319.18	278.86	242.54	MHz
TriMatrix memory M4K block	Simple dual-port RAM 128 × 36 bit	0	1	0	290.86	255.55	222.27	MHz
	True dual-port RAM 128 × 18 bit	0	1	0	290.86	255.55	222.27	MHz
	FIFO 128 × 36 bit	34	1	0	290.86	255.55	222.27	MHz
TriMatrix memory M-RAM block	Single port RAM 4K × 144 bit	1	1	0	255.95	223.06	194.06	MHz
	Simple dual-port RAM 4K × 144 bit	0	1	0	255.95	233.06	194.06	MHz
	True dual-port RAM 4K × 144 bit	0	1	0	255.95	233.06	194.06	MHz
	Single port RAM 8K × 72 bit	0	1	0	278.94	243.19	211.59	MHz
	Simple dual-port RAM 8K × 72 bit	0	1	0	255.95	223.06	194.06	MHz
	True dual-port RAM 8K × 72 bit	0	1	0	255.95	223.06	194.06	MHz
	Single port RAM 16K × 36 bit	0	1	0	280.66	254.32	221.28	MHz
	Simple dual-port RAM 16K × 36 bit	0	1	0	269.83	237.69	206.82	MHz

## Internal Timing Parameters

Internal timing parameters are specified on a speed grade basis independent of device density. Tables 6–36 through 6–42 describe the Stratix GX device internal timing microparameters for LEs, IOEs, TriMatrix™ memory structures, DSP blocks, and MultiTrack interconnects.

**Table 6–36. LE Internal Timing Microparameter Descriptions**

Symbol	Parameter
$t_{SU}$	LE register setup time before clock
$t_H$	LE register hold time after clock
$t_{CO}$	LE register clock-to-output delay
$t_{LUT}$	LE combinational LUT delay for data-in to data-out
$t_{CLR}$	Minimum clear pulse width
$t_{PRE}$	Minimum preset pulse width
$t_{CLKHL}$	Minimum clock high or low time

**Table 6–37. IOE Internal Timing Microparameter Descriptions**

Symbol	Parameter
$t_{SU}$	IOE input and output register setup time before clock
$t_H$	IOE input and output register hold time after clock
$t_{CO}$	IOE input and output register clock-to-output delay
$t_{PIN2COMBOUT\_R}$	Row input pin to IOE combinational output
$t_{PIN2COMBOUT\_C}$	Column input pin to IOE combinational output
$t_{COMBIN2PIN\_R}$	Row IOE data input to combinational output pin
$t_{COMBIN2PIN\_C}$	Column IOE data input to combinational output pin
$t_{CLR}$	Minimum clear pulse width
$t_{PRE}$	Minimum preset pulse width
$t_{CLKHL}$	Minimum clock high or low time

**Table 6–71. EP1SGX40 Row Pin Global Clock External I/O Timing Parameters (Part 2 of 2)**

Symbol	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{OUTCO}}$	2.000	5.365	2.000	5.775	2.000	6.621	ns
$t_{\text{INSUPLL}}$	1.126		1.186		1.352		ns
$t_{\text{INHPLL}}$	0.000		0.000		0.000		ns
$t_{\text{OUTCOPLL}}$	0.500	2.304	0.500	2.427	0.500	2.765	ns

## External I/O Delay Parameters

External I/O delay timing parameters, both for I/O standard input and output adders and programmable input and output delays, are specified by speed grade, independent of device density.

Tables 6–72 through 6–77 show the adder delays associated with column and row I/O pins. If an I/O standard is selected other than LVTTTL 24 mA with a fast slew rate, add the selected delay to the external  $t_{\text{CO}}$  and  $t_{\text{SU}}$  I/O parameters.

**Table 6–72. Stratix GX I/O Standard Column Pin Input Delay Adders (Part 1 of 2)**

I/O Standard	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
LVC MOS		0		0		0	ps
3.3-V LVTTTL		0		0		0	ps
2.5-V LVTTTL		30		31		35	ps
1.8-V LVTTTL		150		157		180	ps
1.5-V LVTTTL		210		220		252	ps
GTL		220		231		265	ps
GTL+		220		231		265	ps
3.3-V PCI		0		0		0	ps
3.3-V PCI-X 1.0		0		0		0	ps
Compact PCI		0		0		0	ps
AGP 1×		0		0		0	ps
AGP 2×		0		0		0	ps
CTT		120		126		144	ps
SSTL-3 class I		–30		–32		–37	ps
SSTL-3 class II		–30		–32		–37	ps

**Table 6–74. Stratix GX I/O Standard Output Delay Adders for Fast Slew Rate on Column Pins (Part 2 of 2)**

Standard	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
GTL+		–110		–115		–133	ps
3.3-V PCI		–230		–241		–277	ps
3.3-V PCI-X 1.0		–230		–241		–277	ps
Compact PCI		–230		–241		–277	ps
AGP 1×		–30		–31		–36	ps
AGP 2×		–30		–31		–36	ps
CTT		50		53		61	ps
SSTL-3 class I		90		95		109	ps
SSTL-3 class II		–50		–52		–60	ps
SSTL-2 class I		100		105		120	ps
SSTL-2 class II		20		21		24	ps
SSTL-18 class I		230		242		278	ps
SSTL-18 class II		0		0		0	ps
1.5-V HSTL class I		380		399		459	ps
1.5-V HSTL class II		190		200		230	ps
1.8-V HSTL class I		380		399		459	ps
1.8-V HSTL class II		390		410		471	ps

**Table 6–75. Stratix GX I/O Standard Output Delay Adders for Fast Slew Rate on Row Pins (Part 1 of 2)**

Standard		-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA		570		599		689	ps
	4 mA		570		599		689	ps
	8 mA		350		368		423	ps
	12 mA		130		137		157	ps
	24 mA		0		0		0	ps
3.3-V LVTTTL	4 mA		570		599		689	ps
	8 mA		350		368		423	ps
	12 mA		130		137		157	ps
	16 mA		70		74		85	ps
	24 mA		0		0		0	ps

**Table 6–77. Stratix GX I/O Standard Output Delay Adders for Slow Slew Rate on Row Pins**

I/O Standard		-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA		1,930		2,031		2,335	ps
	4 mA		1,930		2,031		2,335	ps
	8 mA		1,710		1,800		2,069	ps
	12 mA		1,490		1,569		1,803	ps
3.3-V LVTTTL	4 mA		1,953		2,055		2,363	ps
	8 mA		1,733		1,824		2,097	ps
	12 mA		1,513		1,593		1,831	ps
	16 mA		1,453		1,530		1,759	ps
2.5-V LVTTTL	2 mA		2,632		2,769		3,183	ps
	8 mA		2,052		2,160		2,483	ps
	12 mA		1,942		2,044		2,350	ps
	16 mA		1,902		2,002		2,301	ps
1.8-V LVTTTL	2 mA		4,537		4,773		5,489	ps
	8 mA		3,447		3,628		4,172	ps
	12 mA		3,377		3,555		4,088	ps
1.5-V LVTTTL	2 mA		6,575		6,917		7,954	ps
	4 mA		5,995		6,308		7,253	ps
	8 mA		5,525		5,815		6,686	ps
CTT			1,410		1,485		1,707	ps
SSTL-3 class I			1,450		1,527		1,755	ps
SSTL-3 class II			1,310		1,380		1,586	ps
SSTL-2 class I			1,797		1,892		2,175	ps
SSTL-2 class II			1,717		1,808		2,079	ps
LVDS (1)			1,340		1,411		1,622	ps
LVPECL (1)			1,400		1,474		1,694	ps
3.3-V PCML (1)			1,300		1,369		1,573	ps
HyperTransport technology (1)			1,430		1,506		1,731	ps

**Note to Tables 6–72 through 6–77:**

(1) These parameters are only available on the left side row I/O pins.

**Table 6–87. High-Speed I/O Specifications (Part 3 of 4)** *Notes (1), (2)*

Symbol	Conditions			-5 Speed Grade			-6 Speed Grade			-7 Speed Grade			Unit
				Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
DPA Lock Time	Standard	Training Pattern	Transition Density										
	SPI-4, CSIX	0000 0000 0011 1111 1111	10%	256			256			256			(4)
	Rapid IO	0000 1111	25%	256			256			256			(4)
		1001 0000	50%	256			256			256			(4)
	Misc	1010 1010	100 %	256			256			256			(4)
		0101 0101		256			256			256			(4)
TCCS	All					200			200			300	ps
SW	PCML ( $J = 4, 7, 8, 10$ )			750			750			800			ps
	PCML ( $J = 2$ )			900			900			1,200			ps
	PCML ( $J = 1$ )			1,500			1,500			1,700			ps
	LVDS and LVPECL ( $J = 1$ )			500			500			550			ps
	LVDS, LVPECL, HyperTransport technology ( $J = 2$ through 10)			440			440			500			ps
Input jitter tolerance (peak-to-peak)	All					250			250			250	ps
Output jitter (peak-to-peak)	All					160			160			200	ps
Output $t_{RISE}$	LVDS			80	110	120	80	110	120	80	110	120	ps
	HyperTransport technology			110	170	200	110	170	200	120	170	200	ps
	LVPECL			90	130	150	90	130	150	100	135	150	ps
	PCML			80	110	135	80	110	135	80	110	135	ps

**Table 6–92. Fast PLL Specifications for -7 & -8 Speed Grades (Part 2 of 2)**

Symbol	Parameter	Min	Max	Unit
$t_{DUTY}$	Duty cycle for $DIFFIO\ 1 \times CLKOUT$ pin (3)	45	55	%
$t_{JITTER}$	Period jitter for $DIFFIO$ clock out (3)		$\pm 80$	ps
	Period jitter for internal global or regional clock		$\pm 100$ ps for $>200$ MHz $outclk$ $\pm 20$ mUI for $<200$ MHz $outclk$	ps or mUI
$t_{LOCK}$	Time required for PLL to acquire lock	10	100	$\mu$ s
$m$	Multiplication factors for $m$ counter (4)	1	32	Integer
$l0, l1, g0$	Multiplication factors for $l0, l1$ , and $g0$ counter (4), (5)	1	32	Integer
$t_{ARESET}$	Minimum pulse width on $areset$ signal	10		ns

**Notes to Tables 6–91 & 6–92:**

- (1) See “Maximum Input & Output Clock Rates” on page 6–54.
- (2) When using the SERDES, high-speed differential I/O mode supports a maximum output frequency of 210 MHz to the global or regional clocks (that is, the maximum data rate 840 Mbps divided by the smallest SERDES J factor of 4).
- (3) This parameter is for high-speed differential I/O mode only.
- (4) These counters have a maximum of 32 if programmed for 50/50 duty cycle. Otherwise, they have a maximum of 16.
- (5) High-speed differential I/O mode supports  $W = 1$  to 16 and  $J = 4, 7, 8$ , or 10.

## DLL Jitter

Table 6–93 reports the jitter for the DLL in the DQS phase-shift reference circuit.

**Table 6–93. DLL Jitter for DQS Phase Shift Reference Circuit**

Frequency (MHz)	DLL Jitter (ps)
197 to 200	$\pm 100$
160 to 196	$\pm 300$
100 to 159	$\pm 500$